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# A03423

#### 20V P-Channel MOSFET

# **General Description**

The AO3423 uses advanced trench technology to provide excellent  $R_{\mathrm{DS(ON)}}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a load switch applications.

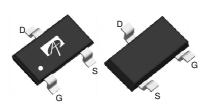
# **Product Summary**

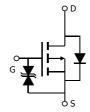
 $\begin{array}{lll} V_{DS} & -20V \\ I_{D} & (at \ V_{GS} \!\!=\! \!\! -10V) & -2A \\ R_{DS(ON)} & (at \ V_{GS} \!\!=\! \!\! -10V) & < 92m\Omega \\ R_{DS(ON)} & (at \ V_{GS} \!\!=\! \!\! -4.5V) & < 118m\Omega \\ R_{DS(ON)} & (at \ V_{GS} \!\!=\! \!\! -2.5V) & < 166m\Omega \end{array}$ 

Typical ESD protection HBM Class 2



SOT23
Top View Bottom View





Absolute Maximum Ratings T<sub>A</sub>=25℃ unless otherwise noted Maximum Units Parameter Symbol Drain-Source Voltage ٧ -20  $V_{DS}$ ٧ Gate-Source Voltage  $V_{GS}$ ±12 T<sub>A</sub>=25℃ -2 Continuous Drain  $I_D$ T<sub>A</sub>=70℃ -2 Current Α Pulsed Drain Current C -17  $\mathbf{I}_{\mathsf{DM}}$ T<sub>A</sub>=25℃ 1.4  $P_D$ W Power Dissipation <sup>B</sup> T<sub>A</sub>=70℃ 0.9 Junction and Storage Temperature Range -55 to 150 C  $T_J$ ,  $T_{STG}$ 

Thermal Characteristics									
Parameter		Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient A	t ≤ 10s	D	65	90	€/M				
Maximum Junction-to-Ambient AD	Steady-State	$R_{\theta JA}$	85	125	€/M				
Maximum Junction-to-Lead	Steady-State	$R_{\theta JL}$	43	60	℃/W				



#### Electrical Characteristics (T<sub>J</sub>=25℃ unless otherwise noted)

Symbol	Parameter	Parameter Conditions		Min	Тур	Max	Units			
STATIC PARAMETERS										
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$		-20			V			
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS}$ =-20V, $V_{GS}$ =0V				-1	μА			
	-		T <sub>J</sub> =55℃			-5				
I <sub>GSS</sub>	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ = ±12V				±10	μΑ			
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{D}=-250\mu A$		-0.5	-0.85	-1.2	V			
$I_{D(ON)}$	On state drain current	$V_{GS}$ =-4.5V, $V_{DS}$ =-5V		-17			Α			
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS}$ =-10V, $I_{D}$ =-2A			76	92	mΩ			
			T <sub>J</sub> =125℃		99	119				
		$V_{GS}$ =-4.5V, $I_{D}$ =-2A			94	118	mΩ			
		$V_{GS}$ =-2.5V, $I_{D}$ =-1A		128	166	mΩ				
g <sub>FS</sub>	Forward Transconductance	$V_{DS}$ =-5V, $I_{D}$ =-2A			6.8		S			
$V_{SD}$	Diode Forward Voltage	$I_S=-1A, V_{GS}=0V$			-0.76	-1	V			
$I_S$	Maximum Body-Diode Continuous Current					-1.5	Α			
DYNAMIC	PARAMETERS									
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =-10V, f=1MHz		250	325	400	pF			
C <sub>oss</sub>	Output Capacitance			40	63	85	pF			
C <sub>rss</sub>	Reverse Transfer Capacitance			22	37	52	pF			
$R_g$	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz			11.2	17	Ω			
SWITCHII	NG PARAMETERS									
$Q_g$	Total Gate Charge	V <sub>GS</sub> =-4.5V, V <sub>DS</sub> =-10V, I <sub>D</sub> =-2A			3.2	4.5	nC			
$Q_{gs}$	Gate Source Charge				0.6		nC			
$Q_{gd}$	Gate Drain Charge				0.9		nC			
t <sub>D(on)</sub>	Turn-On DelayTime	$V_{GS}$ =-10V, $V_{DS}$ =-10V, $R_L$ =5 $\Omega$ , $R_{GEN}$ =3 $\Omega$			11		ns			
t <sub>r</sub>	Turn-On Rise Time				5.5		ns			
t <sub>D(off)</sub>	Turn-Off DelayTime				22		ns			
t <sub>f</sub>	Turn-Off Fall Time				8		ns			
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =-2A, dI/dt=100A/μs			6.1		ns			
$Q_{rr}$	Body Diode Reverse Recovery Charge	I <sub>F</sub> =-2A, dI/dt=100A/μs			1.4		nC			

A. The value of  $R_{\theta JA}$  is measured with the device mounted on  $1in^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25° C. The value in any given application depends on the user's specific board design. B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}=150^\circ$  C, using  $\leqslant$  10s junction-to-ambient thermal resistance. C. Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)}=150^\circ$  C. Ratings are based on low frequency and duty cycles to keep

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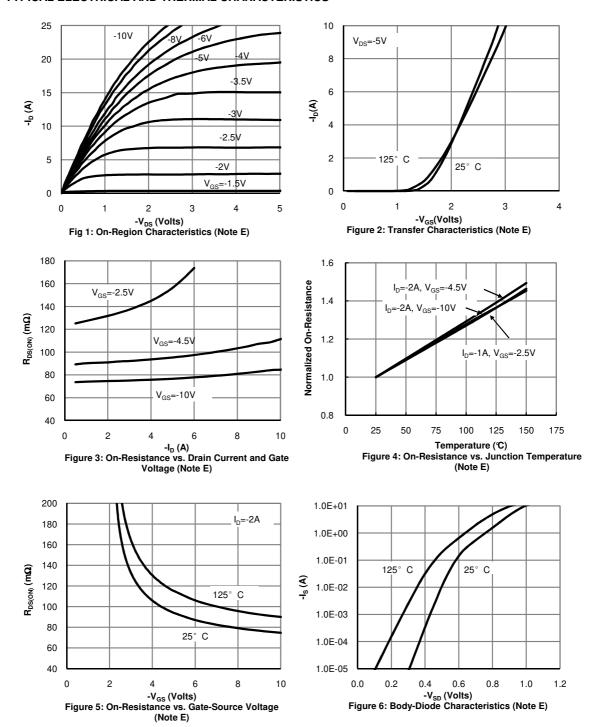
D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of T<sub>J(MAX)</sub>=150° C. The SOA curve provides a single pulse rating.



#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS





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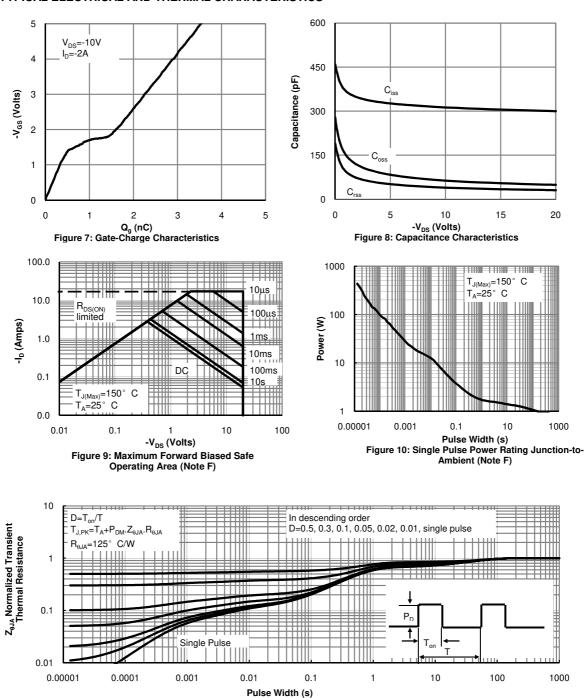
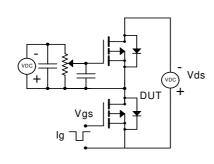
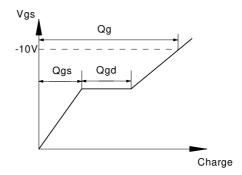


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

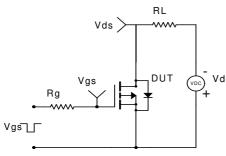


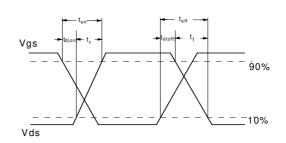
# Gate Charge Test Circuit & Waveform





# Resistive Switching Test Circuit & Waveforms





# Diode Recovery Test Circuit & Waveforms

